## Application/Control No. Applicant(s)/Patent Under Reexamination 10/817,095 HWANG ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Huy D. Nguyen 2681 **U.S. PATENT DOCUMENTS** Document Number Date Country Code-Number-Kind Code Name Classification MM-YYYY US-2003/0207696 11-2003 Willenegger et al. Α 455/522 US-2003/0174645 09-2003 В Paratainen et al. 370/229 US-6,795,419 09-2004 Parantainen et al. C 370/337 D US-US-Ε US-F G US-US-Н US-١ US-US-Κ L US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Code-Number-Kind Code Country Name Classification MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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